

Notice of References Cited	Application/Control No. 10/674,017		Applicant(s)/Patent Under Reexamination BAEK ET AL.	
	Examiner Brian K. Talbot		Art Unit 1762	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,259,926	11-1993	Kuwabara et al.	216/54
*	C	US-5,403,616	04-1995	Hattori et al.	427/126.3
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NON-PATENT DOCUMENTS

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